

Search Notes

Application/Control No.

10/750,599

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

KIM, JAE-WAN

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	551-559, 311,531, 532	2/2/2005	HLN
333	172	2/2/2005	HLN
340	825.71	2/2/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	2/3/2005	HLN
EAST Text Search	2/3/2005	HLN